

Notice of References Cited	Application/Control No. 10/671,115		Applicant(s)/Patent Under Reexamination ARQUIE ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0039132 A1	02-2005	Germain et al.	715/736
*	B	US-2006/0129939 A1	06-2006	Nelles et al.	715/736
*	C	US-2002/0095493 A1	07-2002	Byrnes, Philippe C.	709/224
*	D	US-6,381,036 B1	04-2002	Olson, Thor A.	358/1.9
*	E	US-2003/0225876 A1	12-2003	Oliver et al.	709/224
*	F	US-7,013,433 B1	03-2006	Schorr et al.	715/825
*	G	US-2004/0155900 A1	08-2004	Huang et al.	345/736
*	H	US-2004/0249935 A1	12-2004	Jackson et al.	709/224
*	I	US-2003/0105973 A1	06-2003	Liang et al.	713/200
*	J	US-2002/0024535 A1	02-2002	Ueno et al.	345/736
*	K	US-6,721,290 B1	04-2004	Kondylis et al.	370/329
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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